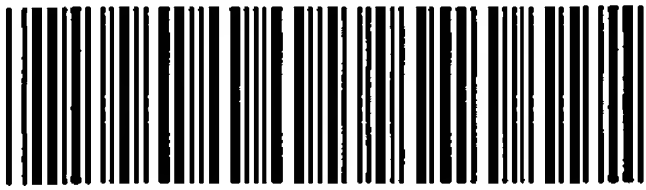


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/661,454	PHAN, HUY D.	
	Examiner	Art Unit	
	John P. Leubecker	3739	

SEARCHED			
Class	Subclass	Date	Examiner
600	104-106,128-130,114,160,182	5/31/2005	JPL
600	153	5/31/2005	JPL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East Text Search	5/31/2005	JPL